Supporting information

Multilevel Storage and Photoinduced-Reset Memory by an Inorganic Perovskite Quantum-Dot/Polystyrene Floating-Gate Organic Transistor

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Figure S1 SEM images of CPB QDs/PS composite films. (a) CPB QDs/PS = 1:1, (b) CPB QDs/PS = 3:1, (c) CPB QDs/PS = 4:1 and (d) CPB QDs/PS = 6:1.



Figure S2 Transfer characteristics ($V_D = -40$ V) of the OFET device based on pentacene with only PS film.



Figure S3 The transfer curves of the pentacene based FGOFETMs in electrical programming and electrical erasing operation mode at $V_{\rm D} = -40$ V.



Figure S4 AFM morphology images of CPB QDs/PS composite films. (a) CPB QDs/PS = 1:1, (b) CPB QDs/PS = 3:1, (c) CPB QDs/PS = 4:1 and (d) CPB QDs/PS = 6:1.



Figure S5 AFM morphology images of pentacene films deposited on CPB QDs/PS composites floating-gate layer. a) CPB QDs/PS = 1:1, b) CPB QDs/PS = 3:1, c) CPB QDs/PS = 4:1 and d) CPB QDs/PS = 6:1.



Figure S6 The transfer curves of the C8-BTBT based FGOFETMs in electrical programming and electrical erasing operation mode at $V_{\rm D} = -40$ V.



Figure S7 The effect of light intensity on the photo-erasure process.



Figure S8 ΔV_{th} related to the voltage program for 10ms during the measure process.



Figure S9 The transfer curves ($V_D = -40$ V) of the pentacene based FGOFETMs under electrical programming and light erasing operation mode with different wavelength (a) 470 nm and (b) 630 nm.